

Notice of References Cited

Application/Control No.

10/064,475

Applicant(s)/Patent Under

Reexamination

CHEN ET AL.

Examiner

Cynthia Britt

Art Unit

2133

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,923,676	07-1999	Sunter et al.	714/733
	B	US-6,023,778	02-2000	Li, Hehching Harry	714/726
	C	US-6,698,006	02-2004	Srinivasan et al.	716/10
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Cost-free Scan: A Low-Overhead Scan Path Design" by Lin et al. in IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, September 1998, page(s): 852 - 861, Volume 17 Issue 9, Inspec Accession Number: 604173
	V	"Test-Point Insertion: Scan Paths Through Functional Logic" by Lin et al. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, Sept. 1998, pages 838 - 851, Volume 17 Issue 9, Inspec Accession Number: 6041730
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.